

Description

The AP6H06S uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = 60V I_{D} = 6.5A$

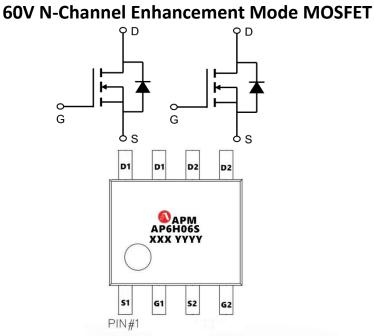
 $R_{DS(ON)}$ <48m Ω @ V_{GS} =10V (Type: 39m Ω)

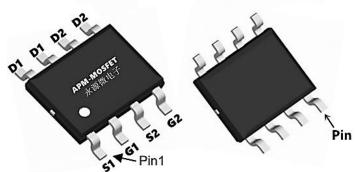
Application

Battery protection

Load switch

Uninterruptible power supply





Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP6H06S	SOP-8L	AP6H06S XXX YYYY	3000

Absolute Maximum Ratings@Ti=25°C(unless otherwise specified)

Symbol	Parameter	rameter Rating	
VDS	Drain-Source Voltage	60	V
VGS	Gate-Source Voltage	±20	V
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	6.0	Α
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V ¹	4.5	Α
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V ¹	11.8	Α
IDM	Pulsed Drain Current	60	A
IAS	Avalanche Current	9.8	A
EAS	Single Pulsed Avalanche Energy	9.3	mJ
P _D @T _C =25°C	Power Dissipation	24	W
TJ, TSTG	Operating and Storage Temperature Range	-55 to +175	°C
R _θ JA	Thermal Resistance Junction-Ambient ¹	62	°C/W
R₀JC	Thermal Resistance Junction-Case ¹	6.3	°C/W





Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	60	65	-	V
IDSS	Zero Gate Voltage Drain Current	V_{DS} =60V, V_{GS} =0V,	-	-	1.0	μA
IGSS	Gate to Body Leakage Current	V_{DS} =0V, V_{GS} =±20V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V_{DS} = V_{GS} , I_D = $250\mu A$	1.2	1.6	2.5	V
DDG()	Static Drain-Source on-Resistance	V _{GS} =10V, I _D =4A	-	39	48	mΩ
RDS(on)		V_{GS} =4.5 V , I_{D} =3 A	-	45	60	mΩ
Ciss	Input Capacitance	V _{DS} =25V, V _{GS} =0V, f=1.0MHz	-	825	-	pF
Coss	Output Capacitance		-	49	-	pF
Crss	Reverse Transfer Capacitance	1 1.00112	-	41	-	pF
Qg	Total Gate Charge	V _{DS} =30V, I _D =4.5A, V _{GS} =10V	-	14	-	nC
Qgs	Gate-Source Charge		_	2.9	-	nC
Qgd	Gate-Drain("Miller") Charge	V 00 10 V	-	5.2	-	nC
td(on)	Turn-on Delay Time	V _{DS} =30V,I _D =2A,	_	5	-	ns
tr	Turn-on Rise Time		_	2.6	-	ns
td(off)	Turn-off Delay Time	R_L =6.7 Ω , R_G =3 Ω , V_{GS} =10 V	-	16.1	-	ns
t _f	Turn-off Fall Time		-	2.3	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	15	Α
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	60	Α
VSD	Drain to Source Diode Forward Voltage	V _{GS} =0V, I _S =15A	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	TJ=25°C,I⊧=15A,	-	35	-	ns
Qrr	Body Diode Reverse Recovery Charge	dl/dt=100A/µs	-	53	-	nC

Note:

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- $2 \sqrt{100} \, \mathrm{The} \, \mathrm{data} \, \mathrm{tested} \, \mathrm{by} \, \mathrm{pulsed}$, pulse width .The EAS data shows Max. rating .
- 3. The test cond \leq 300us duty cycle \leq 2%, duty cycle ition is TJ =25°C, VDD =48V, VG =10V, RG =25 Ω , L=0.1mH, IAS =25A
- 4. The power dissipation is limited by 175 $\!\!\!\!^{\,\circ}\!\!\!\!^{\,\circ}$ junction temperature
- 5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



Typical Characteristics

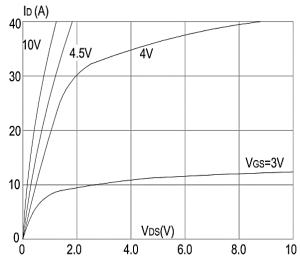


Figure1: Output Characteristics

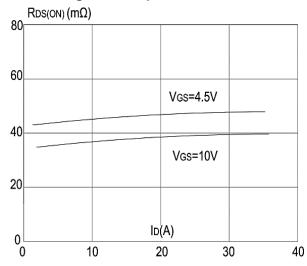


Figure 3:On-resistance vs. Drain Current

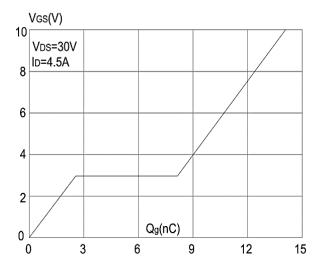


Figure 5: Gate Charge Characteristics

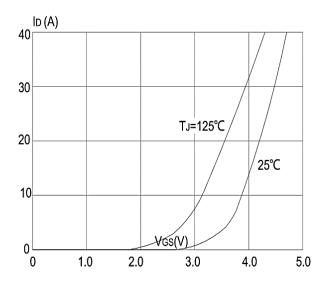


Figure 2: Typical Transfer Characteristics

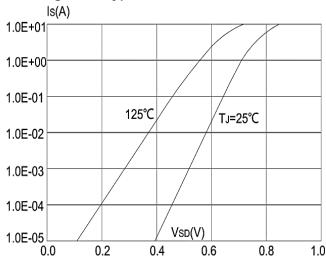


Figure 4: Body Diode Characteristics

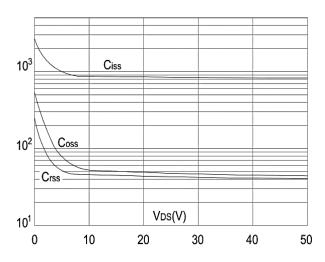
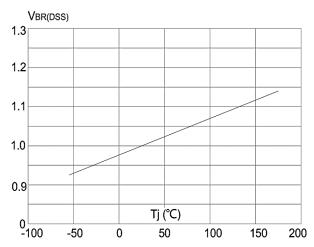


Figure 6: Capacitance Characteristics







RDS(on)

2.5

2.0

1.5

1.0

0.5

-100

-50

0

50

100

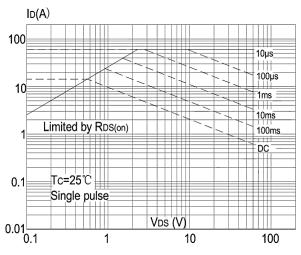
150

200

Figure 7: Normalized Breakdown Voltage vs Junction Temperature

Figure 8: Normalized on Resistance vs.

Junction Temperature



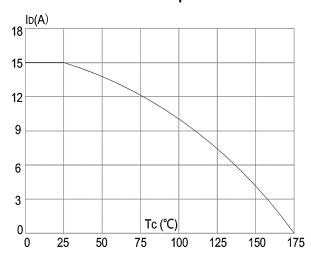


Figure 9: Maximum Safe Operating Area vs. Ambient Temperature

Figure 10: Maximum Continuous Drain Current

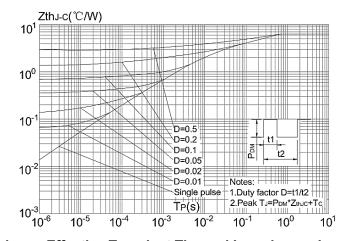
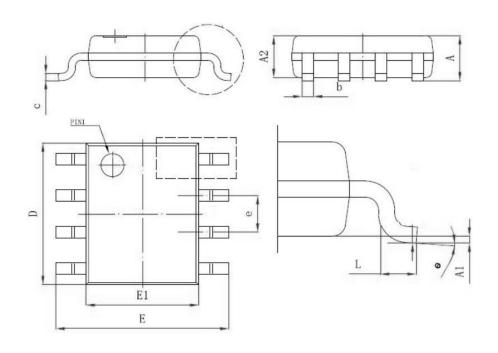


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambien



Package Mechanical Data-SOP-8L



Symbol	Dim in mm			
	Min	Тур	Max	
А	1.35	1.55	1.75	
A1	0.02	0.15	0.25	
A2	1.425	1.45	1.475	
b	0.3	0.4	0.5	
С	0.15	0.2	0.25	
D	4.8	5	5.2	
Е	5.8	6	6.2	
E1	3.8	4	4.2	
е		1.27BSC		
L	0.4		1.27	
θ	0°		8°	



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Edition	Date	Change
REV1.0	2024/1/31	Initial release

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